

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE

**Connectors for electronic equipment – Tests and measurements –  
Part 16-3: Mechanical tests on contacts and terminations – Test 16c: Contact-  
bending strength**

**Connecteurs pour équipements électroniques – Essais et mesures –  
Partie 16-3: Essais mécaniques des contacts et des sorties – Essai 16c: Tenue  
des contacts au pliage**



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## CONNECTORS FOR ELECTRONIC EQUIPMENT – TESTS AND MEASUREMENTS –

### Part 16-3: Mechanical tests on contacts and terminations – Test 16c: Contact-bending strength

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International Standard IEC 60512-16-3 has been prepared by subcommittee 48B, Connectors, of IEC technical committee 48: Electromechanical components and mechanical structures for electronic equipment.

This standard cancels and replaces test 16c of IEC 60512-8, issued in 1993. This standard is to be read in conjunction with IEC 60512-1 and IEC 60512-1-100 which explains the structure of the IEC 60512 series.

The text of this standard is based on the following documents:

FDIS	Report on voting
48B/1885/FDIS	48B/1918/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 60512 series, under the general title *Connectors for electronic equipment – Tests and measurements*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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## CONNECTORS FOR ELECTRONIC EQUIPMENT – TESTS AND MEASUREMENTS –

### Part 16-3: Mechanical tests on contacts and terminations – Test 16c: Contact-bending strength

#### 1 Scope and object

This part of IEC 60512, when required by the detail specification, is used for testing electrical connectors within the scope of technical committee 48. It may also be used for similar devices when specified in a detail specification.

The object of this part of IEC 60512 is to detail a standard test method to determine the ability of a contact to withstand a specified bending moment or force. If so specified in the detail specification, forces other than bending may be applied.

Although this test is illustrated for the mating area of cylindrical contacts, and is particularly applicable to those with a mating diameter of 1,2 mm or less, its use for contacts with other geometries is not excluded. In which case, the detail specification shall contain sufficient detail, given under Clause 6, i), j) and k), to enable the test to be done. Furthermore, it may be used for any part of a connector (such as a keying or polarizing device; cable support or contact latching feature) provided that sufficient detail is given in the detail specification.

NOTE In some cases, IEC 60068-2-21 may be cited in the detail specification.

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IEC 60512-1-1, *Connectors for electronic equipment – Tests and measurements – Part 1-1: General examination – Test 1a: Visual examination*

#### 3 Preparations

##### 3.1 Preparation of specimen

The specimen shall consist of a contact with its terminations, and may be wired if so specified in the detail specification. Any preconditioning given in the detail specification shall be applied.

##### 3.2 Equipment

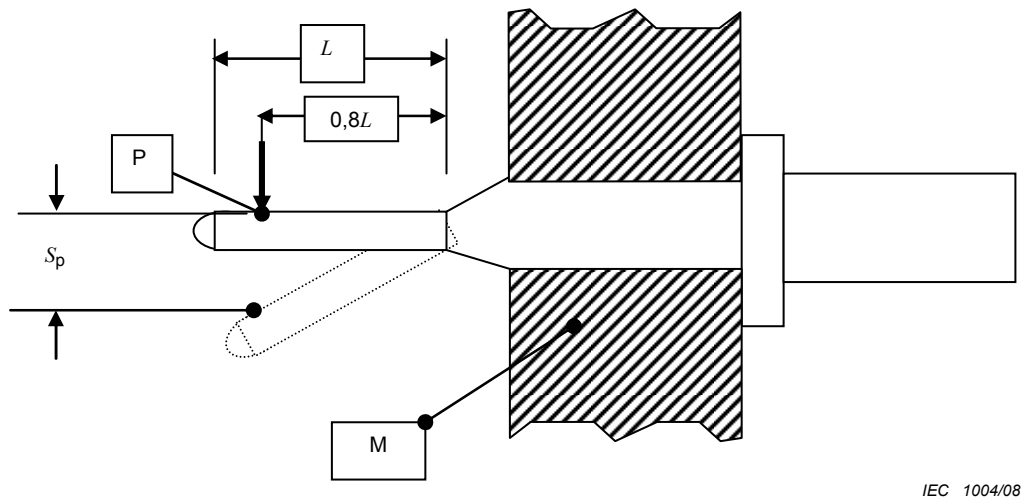
For the application of the specified loads, a suitable device able to provide the controls on the loads (intensity, rate of increase, time of constant load application) shall be required (e.g.: a universal materials testing machine).

If the detail specification requires special preconditioning of the specimen, all the necessary equipment and process steps describing such conditioning shall be included.

4 Mounting

If mounting of the specimen is appropriate, it shall be as specified in the detail specification.

Figure 1 shows an example of mounting and clarifies details to be given in the detail specification.



IEC 1004/08

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Key

- L Full engagement length of the contact under test
- P Point and direction of application of force
- S<sub>p</sub> Permanent set
- M Mounting or support means

Figure 1 – Contact bending (example)

5 Test method

5.1 General

The specified bending moment or force shall be applied, at a specified rate until the specified value is reached. This shall be maintained for 1 minute. The load shall then be removed. This procedure shall be applied at four points mutually at right angles to each other. For solid (e.g. turned) cylindrical contacts that are axi-symmetrical, only one procedure is necessary. If permanent set, exceeding that allowed, results from the foregoing, a new sample shall be used.

NOTE In the case of asymmetric (stamped and formed) contacts, more procedures should be performed choosing 'worst case' positions.

5.2 Measurements and requirements

5.2.1 Before testing

Visual examination according to IEC 60512-1-1 shall be carried out.

### 5.2.2 During testing

The deflection and permanent set of the contact, measured at the point of application of that load shall be measured.

NOTE In the case of a contact being made from a highly resilient material (e.g. spring steel or beryllium copper) the deflection may be large whilst the permanent set is negligible.

The permanent set shall not exceed any value(s) given in the detail specification

### 5.2.3 After testing

Visual examination according to IEC 60512-1-1 shall be carried out.

## 6 Details to be specified

When this test is required by a detail specification, the following shall be given therein.

- a) if preconditioning is required;
- b) if the specimen is to be wired, if so details of this;
- c) if special mounting of the specimen is required;
- d) maximum force to be applied;
- e) point of application of force and relationship to mounting or support means;
- f) rate application of force;
- g) any allowable permanent set;
- h) number of specimens to be tested;
- i) if IEC 60068-2-21 is to be used;
- j) if the geometry of the contact requires special equipment, and if so, details of this;
- k) any deviation from the standard test method.



## **Bibliography**

IEC 60068-2-21:2006, *Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices*

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